

Dual N-Channel Enhancement Mode Field Effect Transistor with Schottky Diode

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A)	Q _g (Typ.)		
30	0.008 at V _{GS} = 10 V	8	15 nC		
30	$0.012 \text{ at V}_{GS} = 4.5 \text{ V}$	6.8	15110		

FEATURES

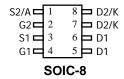
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % UIS Tested
- 100 % R_q Tested
- Compliant to RoHS Directive 2002/95/EC

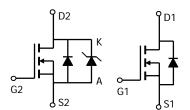


ROHS COMPLIANT HALOGEN FREE

APPLICATIONS

- Set Top Box
- Low Current DC/DC





Absolute Maximum Ratings T_A=25°C unless otherwise noted **Parameter MOSFET** Schottky Units Symbol V_{DS} Drain-Source Voltage 30 V V_{GS} ٧ Gate-Source Voltage ±12 T_A=25°C 8 I_D Continuous Drain Current^A T_△=70°C 6.8 Α Pulsed Drain Current^B I_{DM} 40 V_{KA} Schottky reverse voltage ٧ 30 T_A=25°C 3 I_F Continuous Forward Current^A T_^=70°C 2 Α Pulsed Forward Current^B I_{FM} 40 T_A=25°C 2 2 P_D W T_Δ=70°C 1.44 1.44 **Power Dissipation** T_J , T_{STG} °C Junction and Storage Temperature Range -55 to 150 -55 to 150

Parameter: Thermal Characteris	Symbol	Тур	Max	Units		
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{\theta JA}$	48	62.5		
Maximum Junction-to-Ambient ^A	Steady-State	ГνθЈА	74	110	°C/W	
Maximum Junction-to-Lead ^C	Steady-State R _{0JL}		35	40		
Thermal Characteristics Schottky						
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{ heta JA}$	47.5	62.5		
Maximum Junction-to-Ambient ^A	Steady-State	ıν _θ JA	71	110	°C/W	
Maximum Junction-to-Lead ^C	Steady-State	$R_{ heta JL}$	32	40		



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static			•		l		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, I}_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		32		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.0			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0	1.	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	10			Α	
		V _{GS} = 10 V, I _D = 5 A		0.008		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 4 A		0.012			
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 5 A		16		S	
Dynamic ^b	<u> </u>	- -	I		<u> </u>	l .	
Input Capacitance	C _{iss}			586			
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		117		pF	
Reverse Transfer Capacitance	C _{rss}			55			
<u> </u>		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		15			
Total Gate Charge	Qg			3.7	5.6		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4		nC	
Gate-Drain Charge	Q _{gd}			1.05			
Gate Resistance	R _g	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		55	100		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5$ A, $V_{GEN} = 4.5$ V, $R_g = 1$ Ω		11	22		
Fall Time	t _f			8	16		
Turn-On Delay Time	t _{d(on)}			4	8	ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 3 Ω		9	18		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 5$ A, V_{GEN} = 10 V, R_g = 1 Ω		10	20		
Fall Time	t _f			6	12		
Drain-Source Body Diode Characteristi	cs		•				
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.25	Δ	
Pulse Diode Forward Current	I _{SM}				24	A	
Body Diode Voltage	V_{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 5 A, dI/dt = 100 A/µs, T _J = 25 °C		4	8	nC	
Reverse Recovery Fall Time	ta	$_{1F} = 3 \text{ A}$, $_{U/U}U = 100 \text{ A/}\mu \text{ S}$, $_{1J} = 23 \text{ C}$		7			
Reverse Recovery Rise Time	t _b	_		4		ns	

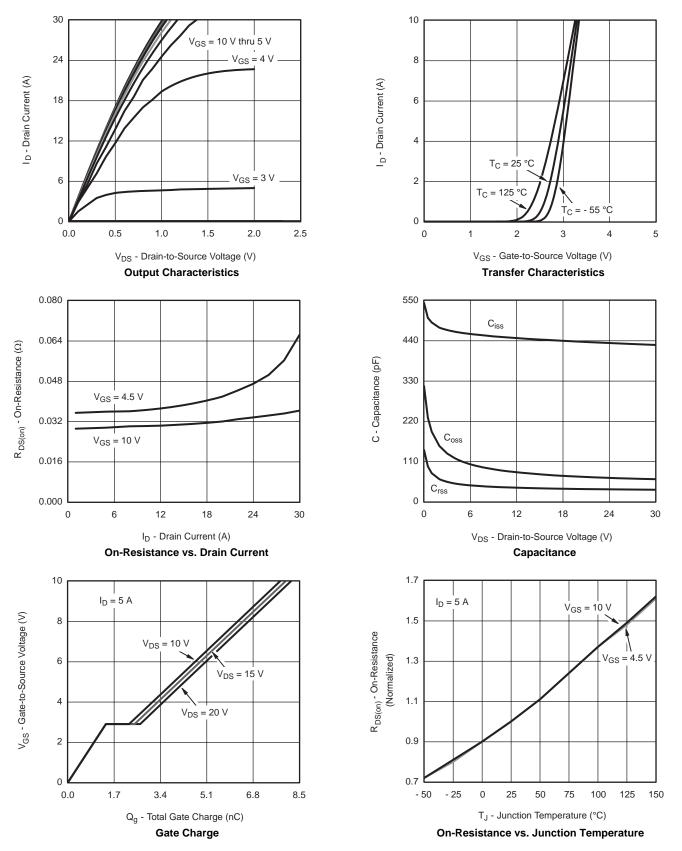
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



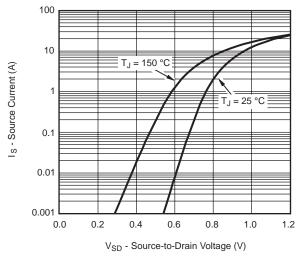
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



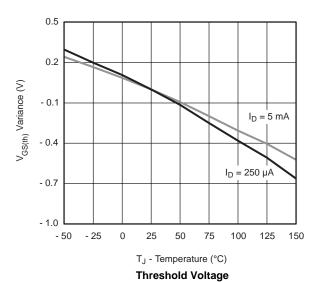


 $I_D = 5 A$

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Source-Drain Diode Forward Voltage



0.12 0.09 Up 12 0.09 U

4 5

2

3

0.15

0.00

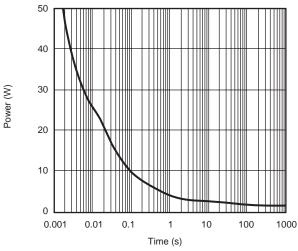
0

V_{GS} - Gate-to-Source Voltage (V)

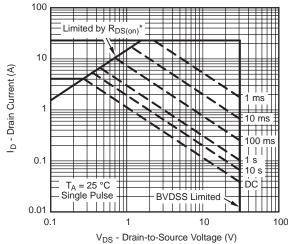


6

8 9



Single Pulse Power

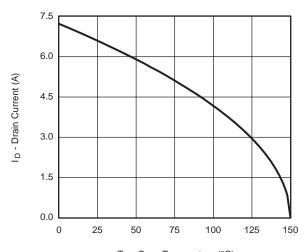


 * V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

Safe Operating Area, Junction-to-Ambient

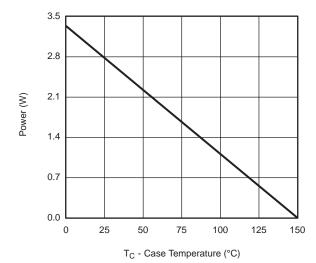


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

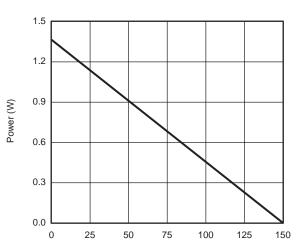


T_C - Case Temperature (°C)





Power, Junction-to-Foot



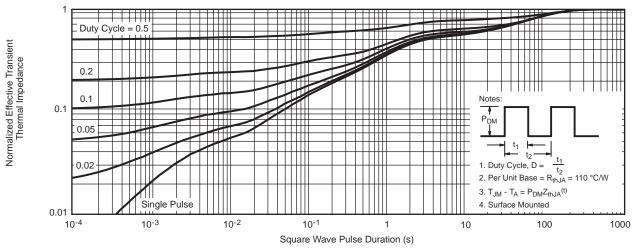
T_A - Ambient Temperature (°C)

Power, Junction-to-Ambient

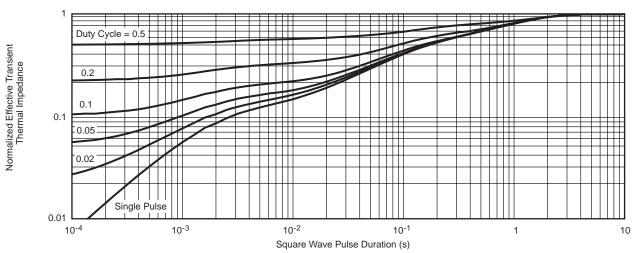
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



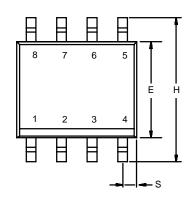
Normalized Thermal Transient Impedance, Junction-to-Ambient

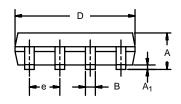


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







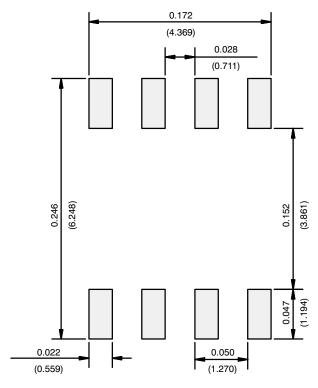
	MILLIMETERS		INC	HES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sen-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

Return to Index



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